SONY

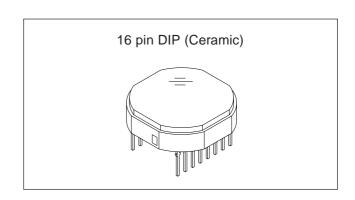
ICX419AKB

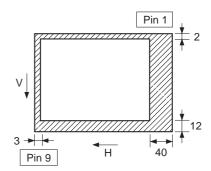
Diagonal 8mm (Type 1/2) CCD Image Sensor for PAL Color Video Cameras

Description

The ICX419AKB is an interline CCD solid-state image sensor suitable for PAL color video cameras with a diagonal 8mm (Type 1/2) system. Compared with the current product ICX039DNB, basic characteristics such as sensitivity, smear, dynamic range and S/N are improved drastically.

This chip features a field period readout system and an electronic shutter with variable charge-storage time. Also, this outline is miniaturized by using original package. This chip is compatible with the pins of the ICX039DNB and has the same drive conditions.





Optical black position (Top View)

Features

- High sensitivity (+6.0dB compared with the ICX039DNB)
- Low smear (-5.0dB compared with the ICX039DNB)
- High D range (+3.0dB compared with the ICX039DNB)
- High S/N
- High resolution and low dark current
- · Excellent antiblooming characteristics
- Ye, Cy, Mg, and G complementary color mosaic filters on chip
- Continuous variable-speed shutter

• Substrate bias: Adjustment free (external adjustment also possible with 6 to 14V)

Reset gate pulse: 5Vp-p adjustment free (drive also possible with 0 to 9V)

Horizontal register: 5V drive
Maximum package dimensions: \$\phi13.2mm

Device Structure

• Interline CCD image sensor

• Optical size: Diagonal 8mm (Type 1/2)

Number of effective pixels: 752 (H) × 582 (V) approx. 440K pixels
 Total number of pixels: 795 (H) × 596 (V) approx. 470K pixels

• Chip size: 7.40mm (H) \times 5.95mm (V) • Unit cell size: 8.6 μ m (H) \times 8.3 μ m (V)

• Optical black: Horizontal (H) direction: Front 3 pixels, rear 40 pixels

Vertical (V) direction: Front 12 pixels, rear 2 pixels

Number of dummy bits: Horizontal 22

Vertical 1 (even fields only)

Substrate material: Silicon

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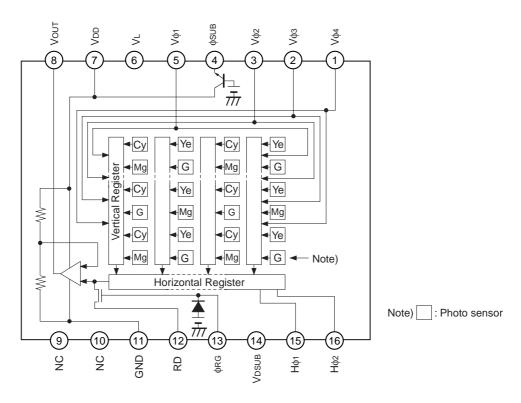
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Block Diagram and Pin Configuration

(Top View)



Pin Description

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	Vф4	Vertical register transfer clock	9	NC	
2	Vфз	Vertical register transfer clock	10	NC	
3	Vф2	Vertical register transfer clock	11	GND	GND
4	фѕив	Substrate clock	12	RD	Reset drain bias
5	Vф1	Vertical register transfer clock	13	фRG	Reset gate clock
6	VL	Protective transistor bias	14	VDSUB	Substrate bias circuit supply voltage
7	Vdd	Output circuit supply voltage	15	Нф1	Horizontal register transfer clock
8	Vout	Signal output	16	Нф2	Horizontal register transfer clock

Absolute Maximum Ratings

	Item	Ratings	Unit	Remarks
Substrate clock ϕ su	в – GND	-0.3 to +50	V	
Cupply voltage	Vdd, Vrd, Vdsub, Vout – GND	-0.3 to +18	V	
Supply voltage	Vdd, Vrd, Vdsub, Vout — фsub	-55 to +10	V	
Clask innut valtage	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-15 to +20	V	
Clock input voltage	Vφ1, Vφ2, Vφ3, Vφ4 – φsuв	to +10	V	
Voltage difference b	etween vertical clock input pins	to +15	V	*1
Voltage difference b	etween horizontal clock input pins	to +17	V	
Hφ1, Hφ2 – Vφ4		-17 to +17	V	
φRG – GND		-10 to +15	V	
фRG — фSUB		-55 to +10	V	
VL — фSUB		-65 to +0.3	V	
Pins other than GN	D and фsuв – VL	-0.3 to +30	V	
Storage temperature	е	-30 to +80	°C	
Operating temperate	ure	-10 to +60	°C	

 $^{^{*1}\,}$ +27V (Max.) when clock width < 10µs, clock duty factor < 0.1%.

Bias Conditions 1 [when used in substrate bias internal generation mode]

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output circuit supply voltage	VDD	14.55	15.0	15.45	V	
Reset drain voltage	VRD	14.55	15.0	15.45	V	VRD = VDD
Protective transistor bias	VL		*1			
Substrate bias circuit supply voltage	VDSUB	14.55	15.0	15.45	V	
Substrate clock	фѕив		*2			

^{*1} VL setting is the VvL voltage of the vertical transfer clock waveform, or the same supply voltage as the VL power supply for the V driver should be used. (When CXD1267AN is used.)

Bias Conditions 2 [when used in substrate bias external adjustment mode]

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output circuit supply voltage	VDD	14.55	15.0	15.45	V	
Reset drain voltage	VRD	14.55	15.0	15.45	V	VRD = VDD
Protective transistor bias	VL		*3			
Substrate bias circuit supply voltage	VDSUB		*4			
Substrate voltage adjustment range	VsuB	6.0		14.0	V	*5
Substrate voltage adjustment precision	ΔVsub	-3		+3	%	*5

^{*3} VL setting is the V_{VL} voltage of the vertical transfer clock waveform, or the same supply voltage as the V_L power supply for the V driver should be used. (When CXD1267AN is used.)

Vsub code — one character indication

Code and optimal setting correspond to each other as follows.

VsuB code	Е	f	G	h	J	K	L	m	N	Р	Q	R	S	Т	U	V	W
Optimal setting	6.0	6.5	7.0	7.5	8.0	8.5	9.0	9.5	10.0	10.5	11.0	11.5	12.0	12.5	13.0	13.5	14.0

<Example> "L" \rightarrow Vsub = 9.0V

DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output circuit supply current	IDD		5.0	10.0	mA	

^{*2} Do not apply a DC bias to the substrate clock pin, because a DC bias is generated within the CCD.

^{*4} Connect to GND or leave open.

^{*5} The setting value of the substrate voltage (Vsub) is indicated on the back of the image sensor by a special code. When adjusting the substrate voltage externally, adjust the substrate voltage to the indicated voltage. The adjustment precision is ±3%. However, this setting value has not significance when used in substrate bias internal generation mode.

Clock Voltage Conditions

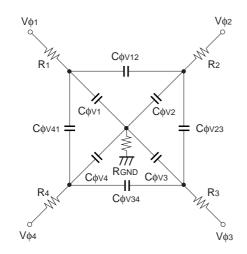
Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	Vvт	14.55	15.0	15.45	V	1	
	Vvh1, Vvh2	-0.05	0	0.05	V	2	$V_{VH} = (V_{VH1} + V_{VH2})/2$
	VvH3, VvH4	-0.2	0	0.05	V	2	
	VVL1, VVL2, VVL3, VVL4	-9.6	-9.0	-8.5	V	2	VVL = (VVL3 + VVL4)/2
	Vφv	8.3	9.0	9.65	Vp-p	2	$V\phi V = VVHN - VVLN (n = 1 to 4)$
Vertical transfer clock	VvH1 — VvH2			0.1	V	2	
voltage	VvH3 — VvH	-0.25		0.1	V	2	
	Vvh4 – Vvh	-0.25		0.1	V	2	
	Vvнн			0.5	V	2	High-level coupling
	Vvhl			0.5	V	2	High-level coupling
	VVLH			0.5	V	2	Low-level coupling
	VVLL			0.5	V	2	Low-level coupling
Horizontal transfer	Vфн	4.75	5.0	5.25	Vp-p	3	
clock voltage	VHL	-0.05	0	0.05	V	3	
	VRGL		*1		V	4	
Reset gate clock voltage*1	Vþrg	4.5	5.0	5.5	Vp-p	4	
1 5.1.5.90	Vrglh – Vrgll			0.8	V	4	Low-level coupling
Substrate clock voltage	Vфsuв	23.0	24.0	25.0	Vp-p	5	

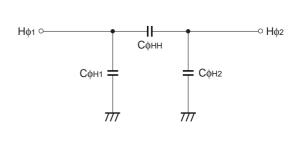
^{*1} Input the reset gate clock without applying a DC bias. In addition, the reset gate clock can also be driven with the following specifications.

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Reset gate clock	VRGL	-0.2	0	0.2	V	4	
voltage	Vþrg	8.5	9.0	9.5	Vp-p	4	

Clock Equivalent Circuit Constant

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer clock	Сф∨1, Сф∨3		3300		pF	
and GND	C φν2, C φν4		3300		pF	
Capacitance between vertical transfer clocks	СфV12, СфV34		820		pF	
Capacitance between vertical transier clocks	Сф∨23, Сф∨41		330		pF	
Capacitance between horizontal transfer clock	Сфн1		120		pF	
and GND	Сфн2		91		pF	
Capacitance between horizontal transfer clocks	Сфнн		47		pF	
Capacitance between reset gate clock and GND	C¢RG		11		pF	
Capacitance between substrate clock and GND	Сфѕив		680		pF	
Vertical transfer clock series resistor	R1, R3		75		Ω	
vertical transfer clock series resistor	R2, R4		82		Ω	
Vertical transfer clock ground resistor	RGND		68		Ω	



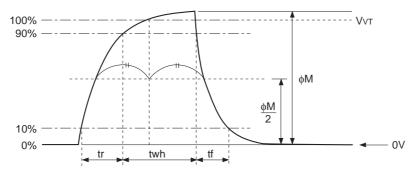


Vertical transfer clock equivalent circuit

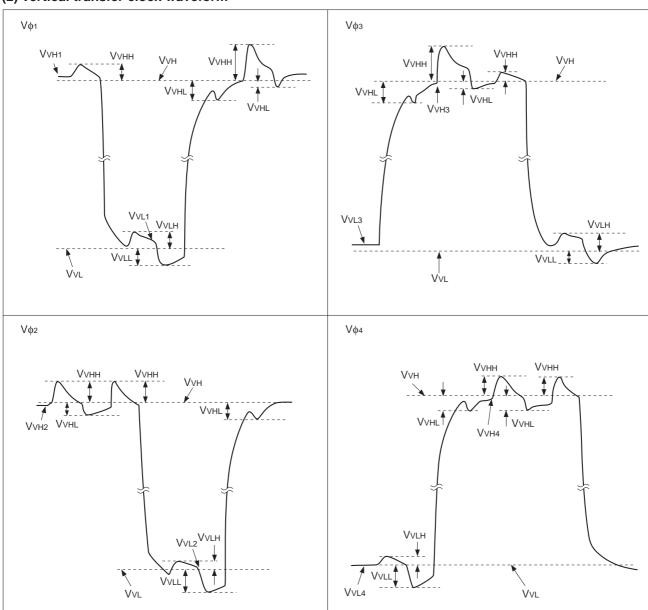
Horizontal transfer clock equivalent circuit

Drive Clock Waveform Conditions

(1) Readout clock waveform



(2) Vertical transfer clock waveform

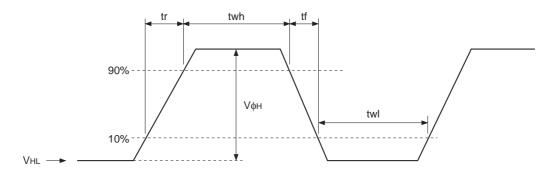


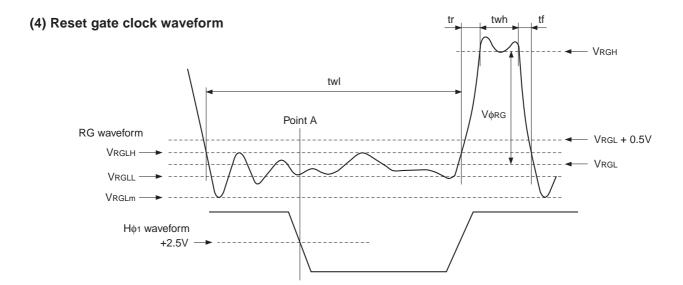
VvH = (VvH1 + VvH2)/2

VvL = (VvL3 + VvL4)/2

 $V\phi v = Vvhn - Vvhn (n = 1 to 4)$

(3) Horizontal transfer clock waveform





VRGLH is the maximum value and VRGLL is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG. In addition, VRGL is the average value of VRGLH and VRGLL.

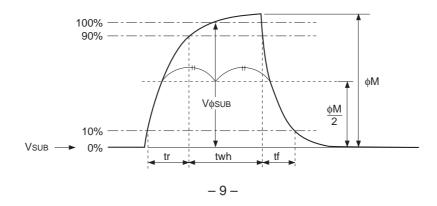
$$V_{RGL} = (V_{RGLH} + V_{RGLL})/2$$

Assuming VRGH is the minimum value during the period twh, then:

$$V\phi RG = VRGH - VRGL$$

Negative overshoot level during the falling edge of RG is VRGLm.

(5) Substrate clock waveform



Clock Switching Characteristics

	ltom	Symbol		twh			twl			tr			tf		Unit	Remarks	
	Item	Symbol	Min.	Тур.	Мах.	Min.	Тур.	Max.	Min.	Тур.	Мах.	Min.	Тур.	Мах.	Unit	Remarks	
Rea	adout clock	VT	2.3	2.5					0.5			0.5			μs	During readout	
Ver cloc	tical transfer ck	Vφ1, Vφ2, Vφ3, Vφ4										15		250	ns	*1	
Horizontal transfer clock	During imaging	Нф		20			20			15	19		15	19	ns	*2	
rizon nsfer	During	Нф1		5.38						0.01			0.01				
Ho	parallel-serial conversion	Нф2					5.38			0.01			0.01		μs		
Res	set gate clock	φRG	11	13			51			3			3		ns		
Sub	strate clock	φSUB	1.5	1.8							0.5			0.5	μs	When draining charge	

^{*1} When vertical transfer clock driver CXD1267AN is used.

^{*2} $tf \ge tr - 2ns$.

Itom	Symbol	Symbol two			Linit	Domorko
Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Horizontal transfer clock	Нф1, Нф2	16	20		ns	*3

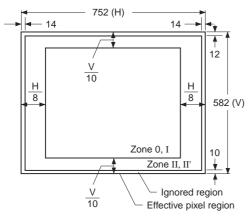
^{*3} The overlap period for twh and twl of horizontal transfer clocks $H\phi_1$ and $H\phi_2$ is two.

Image Sensor Characteristics

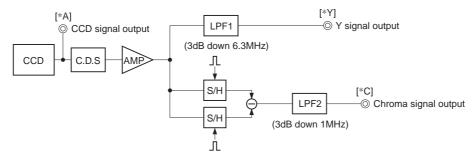
 $(Ta = 25^{\circ}C)$

Item	Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	1040	1300		mV	1	
Saturation signal	Ysat	1000			mV	2	Ta = 60°C
Smear	Sm		-115	-105	dB	3	
Video signal sheding	CHV			20	%	4	Zone 0 and I
Video signal shading	SHy			25	%	4	Zone 0 to II'
Uniformity between	ΔSr			10	%	5	
video signal channels	ΔSb			10	%	5	
Dark signal	Ydt			2	mV	6	Ta = 60°C
Dark signal shading	ΔYdt			1	mV	7	Ta = 60°C
Flicker Y	Fy			2	%	8	
Flicker R-Y	Fcr			5	%	8	
Flicker B-Y	Fcb			5	%	8	
Line crawl R	Lcr			3	%	9	
Line crawl G	Lcg			3	%	9	
Line crawl B	Lcb			3	%	9	
Line crawl W	Lcw			3	%	9	
Lag	Lag			0.5	%	10	

Zone Definition of Video Signal Shading



Measurement System



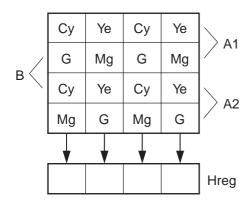
Note) Adjust the amplifier gain so that the gain between [*A] and [*Y], and between [*A] and [*C] equals 1.

Image Sensor Characteristics Measurement Method

Measurement conditions

- In the following measurements, the device drive conditions are at the typical values of the bias and clock voltage conditions. (when used with substrate bias external adjustment, set the substrate voltage to the value indicated on the device.)
- 2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black level (OB) is used as the reference for the signal output, which is taken as the value of Y signal output or chroma signal output of the measurement system.

O Color coding of this image sensor & Composition of luminance (Y) and chroma (color difference) signals



As shown in the left figure, fields are read out. The charge is mixed by pairs such as A1 and A2 in the A field. (pairs such as B in the B field)

As a result, the sequence of charges output as signals from the horizontal shift register (Hreg) is, for line A1, (G + Cy), (Mg + Ye), (G + Cy), and (Mg + Ye).

Color Coding Diagram

These signals are processed to form the Y signal and chroma (color difference) signal. The Y signal is formed by adding adjacent signals, and the chroma signal is formed by subtracting adjacent signals. In other words, the approximation:

$$Y = \{(G + Cy) + (Mg + Ye)\} \times 1/2$$

= 1/2 {2B + 3G + 2R}

is used for the Y signal, and the approximation:

$$R - Y = \{(Mg + Ye) - (G + Cy)\}\$$

= $\{2R - G\}$

is used for the chroma (color difference) signal. For line A2, the signals output from Hreg in sequence are

$$(Mg + Cy), (G + Ye), (Mg + Cy), (G + Ye).$$

The Y signal is formed from these signals as follows:

$$Y = \{(G + Ye) + (Mg + Cy)\} \times 1/2$$

= 1/2 {2B + 3G + 2R}

This is balanced since it is formed in the same way as for line A1.

In a like manner, the chroma (color difference) signal is approximated as follows:

$$-(B-Y) = \{(G + Ye) - (Mg + Cy)\}\$$

= $-\{2B - G\}$

In other words, the chroma signal can be retrieved according to the sequence of lines from R - Y and - (B - Y) in alternation. This is also true for the B field.

Definition of standard imaging conditions

1) Standard imaging condition I:

Use a pattern box (luminance 706cd/m², color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F5.6. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.

2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

1. Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/250s, measure the Y signal (Ys) at the center of the screen and substitute the value into the following formula.

$$S = Ys \times \frac{250}{50} [mV]$$

2. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with average value of the Y signal output, 200mV, measure the minimum value of the Y signal.

3. Smear

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity to 500 times the intensity with average value of the Y signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value YSm [mV] of the Y signal output and substitute the value into the following formula.

Sm =
$$20 \times log \left(\frac{YSm}{200} \times \frac{1}{500} \times \frac{1}{10} \right)$$
 [dB] (1/10V method conversion value)

4. Video signal shading

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity so that the average value of the Y signal output is 200mV. Then measure the maximum (Ymax [mV]) and minimum (Ymin [mV]) values of the Y signal and substitute the values into the following formula.

SHy =
$$(Ymax - Ymin)/200 \times 100 [\%]$$

5. Uniformity between video signal channels

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the maximum (Crmax, Cbmax [mV]) and minimum (Crmin, Cbmin [mV]) values of the R - Y and B - Y channels of the chroma signal and substitute the values into the following formula.

$$\Delta Sr = | (Crmax - Crmin)/200 | \times 100 [\%]$$

 $\Delta Sb = | (Cbmax - Cbmin)/200 | \times 100 [\%]$

6. Dark signal

Measure the average value of the Y signal output (Ydt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

7. Dark signal shading

After measuring 6, measure the maximum (Ydmax [mV]) and minimum (Ydmin [mV]) values of the dark signal output and substitute the values into the following formula.

 $\Delta Ydt = Ydmax - Ydmin [mV]$

8. Flicker

1) Fy

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the difference in the signal level between fields (Δ Yf [mV]). Then substitute the value into the following formula.

$$Fy = (\Delta Yf/200) \times 100 [\%]$$

2) Fcr, Fcb

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, insert an R or B filter, and then measure both the difference in the signal level between fields of the chroma signal (Δ Cr, Δ Cb) as well as the average value of the chroma signal output (CAr, CAb). Substitute the values into the following formula.

Fci =
$$(\Delta Ci/CAi) \times 100$$
 [%] (i = r, b)

9. Line crawls

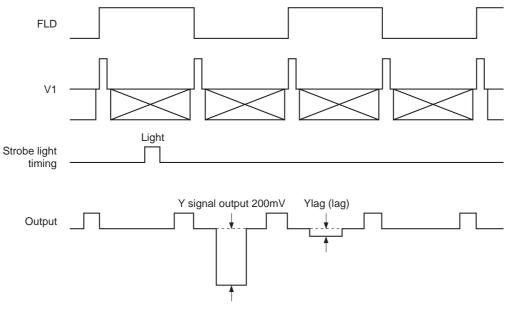
Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then insert a white subject and R, G, and B filters and measure the difference between Y signal lines for the same field (Δ YIw, Δ YIr, Δ YIg, Δ YIb [mV]). Substitute the values into the following formula.

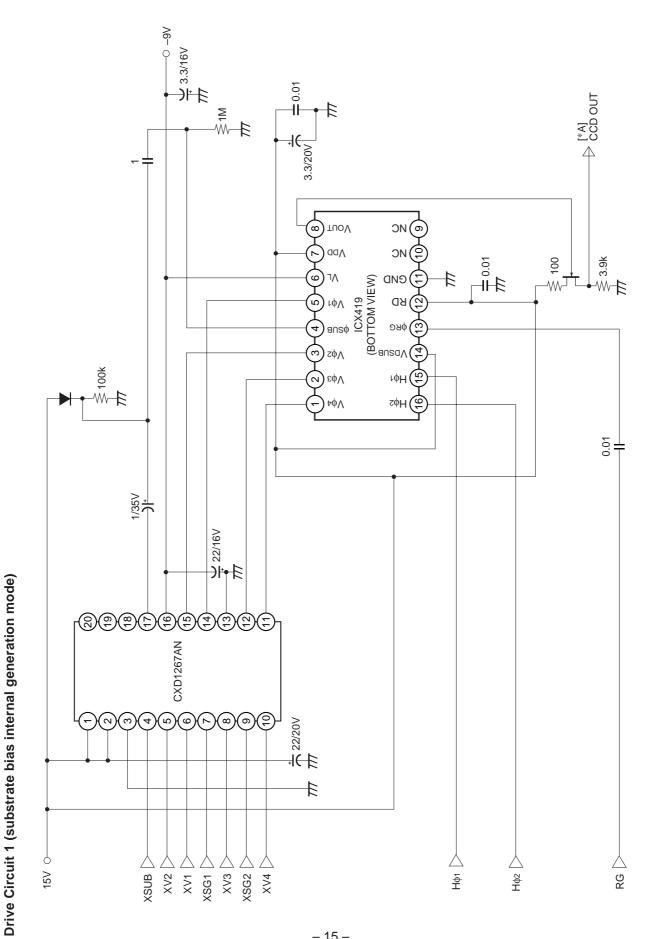
Lci =
$$(\Delta Y li/200) \times 100 [\%]$$
 (i = w, r, g, b)

10. Lag

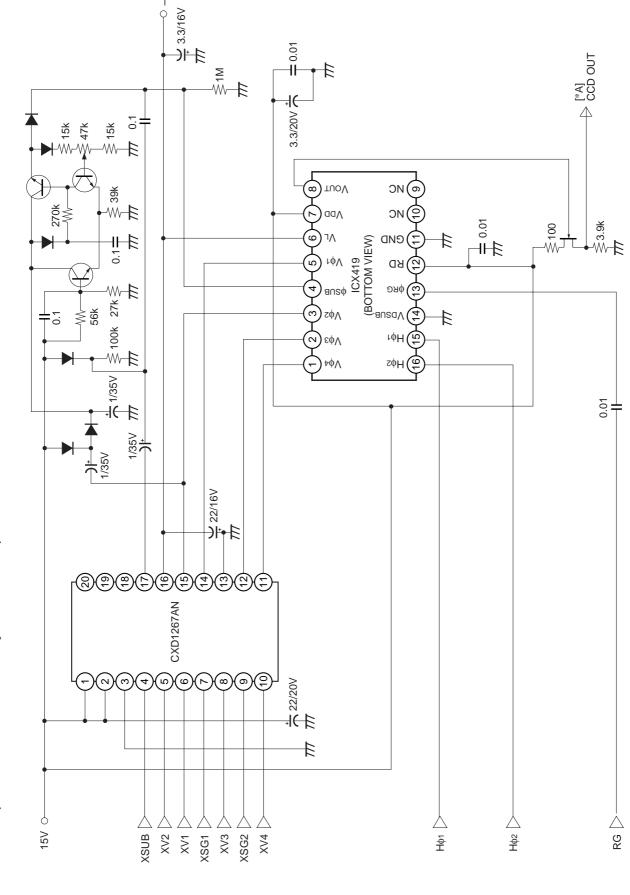
Adjust the Y signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Ylag). Substitute the value into the following formula.

$$Lag = (Ylag/200) \times 100 [\%]$$



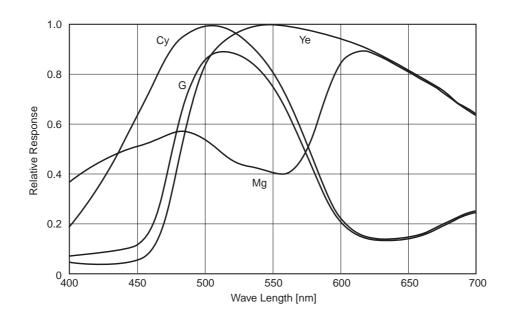


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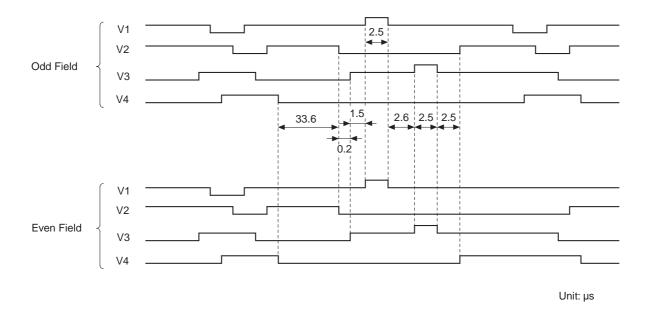


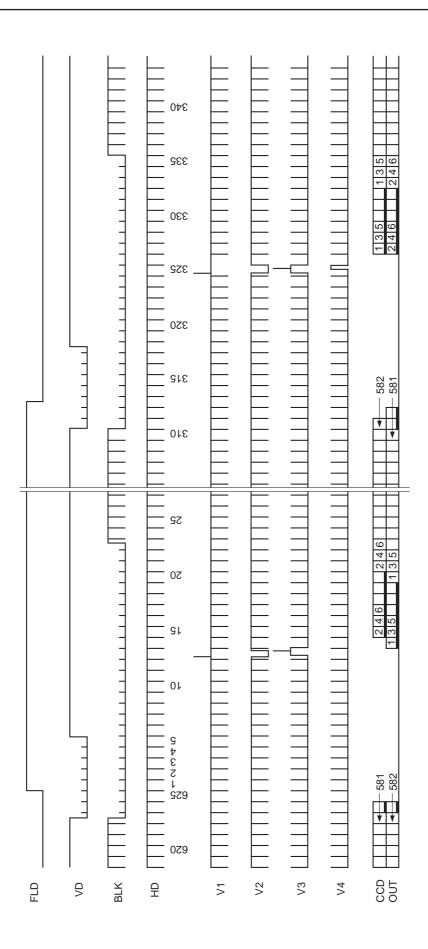
Drive Circuit 2 (substrate bias external adjustment mode)

Spectral Sensitivity Characteristics (Excludes lens characteristics and light source characteristics)

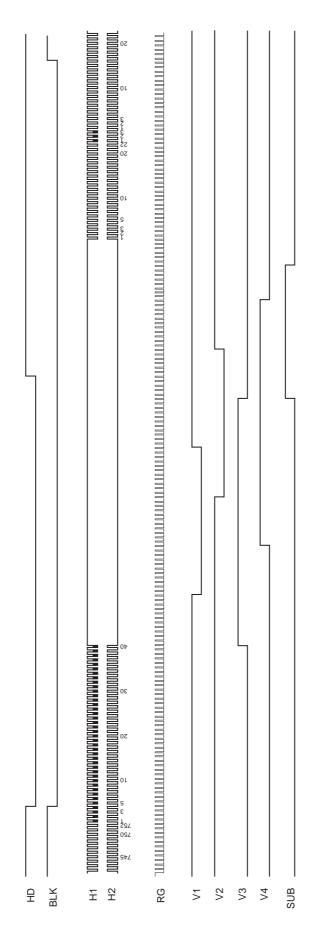


Sensor Readout Clock Timing Chart









Notes on Handling

1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

3) Dust and dirt protection

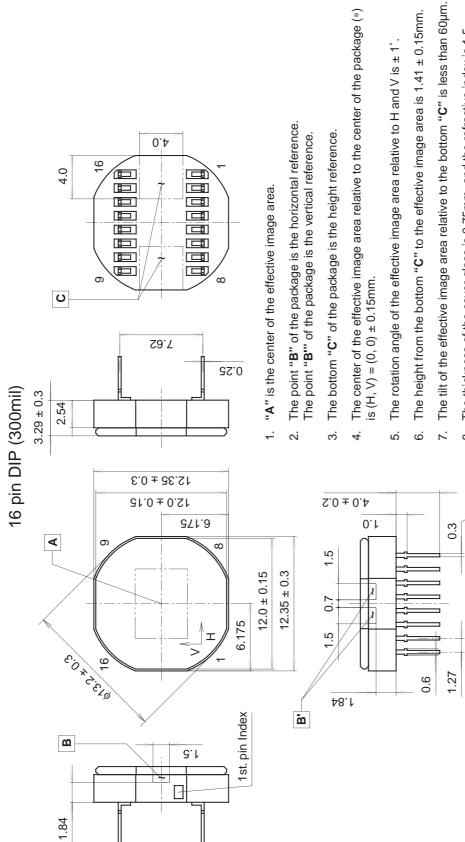
Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operations as required, and use them.

- a) Perform all assembly operations in a clean room (class 1000 or less).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.
- 4) Do not expose to strong light (sun rays) for long periods. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- 5) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- 6) CCD image sensors are precise optical equipment that should not be subject to too much mechanical shocks.

Package Outline

Unit: mm





- The thickness of the cover glass is 0.75mm, and the refractive index is 1.5. ω.
- * Center of the package : The center is halfway between two pairs of opposite sides, as measured from "B", "B". 0.3 M

Φ

GOLD PLATING

Ceramic

PACKAGE MATERIAL

LEAD TREATMENT

PACKAGE STRUCTURE

42 ALLOY

AS-B4-01(E)

DRAWING NUMBER

PACKAGE MASS LEAD MATERIAL

0.90g